

<b>Notice of References Cited</b>	Application/Control No. 10/627,782	Applicant(s)/Patent Under Reexamination KAWANISHI ET AL.	
	Examiner John D. Lee <i>John D. Lee</i>	Art Unit 2874	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,532,867	07-1996	Hayes et al.	359/329
*	B	US-6,259,836	07-2001	Dodds, David E.	385/24
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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